

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10777470	LEE ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Mui, Christine T	1709	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
204	450	07.11.2007	CTM
366	341	07.11.2007	CTM
422	100, 101	07.11.2007	CTM
435	287.3	07.11.2007	CTM
436	052	07.11.2007	CTM
516	073	07.30.2007	CTM

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
See EAST Search Report	07.10.2007	CTM
See Updated EAST Search Report	07 April 2008	CTM
See Updated EAST Search Report	17 December 2008	CTM
See Updated EAST Search Report	07 April 2009	CTM

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	See Interference Search Report	07 April 2009	CTM